

Please type a plus sign (+) inside this box



PTO/SB/08A (08-00)

Approved for use through 10/31/2002. OMB 0651-0031

Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it displays a valid OMB control number.

Substitute for Form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Complete If Known	
				Application Number	10728068
				Filing Date	12/4/03
				First Named Inventor	Steinmann et al.
				Group Art Unit	2826
Examiner Name	Dolan				
Sheet	1	of	1	Attorney Docket No.	TI-36776

U.S. PATENT DOCUMENTS						
Exam. Initials*	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Doc.	Date of Pub. of Cited Doc. (mm-dd-yyyy)	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
NMD	AA	6,497,824	B1	Chen et al.	12/24/2002	Entire Document
	AB					

FOREIGN PATENT DOCUMENTS								
Exam. Initials*	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Doc.	Date of Pub. of Cited Doc. (mm-dd-yyyy)	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ³
		Office ³	Number ⁴	Kind Code ² (if known)				
	BA							

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS					
Exam. Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T ²
NMD	CA	"Characterization of Bolometers Based on Polycrystalline Silicon Germanium Alloys", S. SEDKY, P. FIORINI, M. CAYMAX, C. BAERT, L. HERMANS and R. MERTENS, IEEE Electron Device Letters, Vol. 19, No. 10, October 1998, pp.376-378.			
NMD	CB	"Analysis of Distributed Resistance Effects in MOS Transistors", JOHN HORAN, COLIN LYDEN, ALAN MATHEWSON, CIARAN C. CAHILL and W. A. LANE, IEEE Transactions on Computer Aided Design, Volume 8, No. 1, January 1989, pp. 41-45.			
NMD	CC	"A Technique for Electrically Measuring the Thermal Resistance of GaAs Bulk Resistors", Edwin Sabin, John Scarpulla, Yeong-Chang Chou and Gene Shimamoto, GaAs Reliability Workshop, 2000, Proceedings, pp. 65-69.			
NMD	CD	"Heat Transport in Thin Dielectric Films", S.M. LEE and DAVID G. CAHILL, J. Appl. Phys., American Institute of Physics, Volume 81, March 1997, pp. 2590-2595.			
NMD	CE	"Effect of Thickness on the Transverse Thermal conductivity of Thin Dielectric Films", A.J. GRIFFIN, JR., F.R. BROTZEN, and P.J. LOOS, J. Appl. Phys., American Institute of Physics, Volume 75, April 1994, pp. 3761-3764.			
NMD	CF	"Integration of Thin Film MIM Capacitors and Resistors into Copper Metallization Based RF-CMOS and Bi-CMOS Technologies", PETER ZURCHER, PRASAD ALLURI, PEIR CHU, ALAIN DUVALLET, CHRIS HAPP, RASHAUNDA HENERSON, JOHN MENDONCA, MATTHEW KIM, MICHAEL PETRAS, MARK RAYMOND, TOM REMMEL, DOUG ROBERTS, BOB STEIMLE, JIM STIPANUK, SHERRY STRAUB, TERRY SPARKS, MARC TARABBIA, HELENE THIBIEROZ and MEL MILLER, Electron Devices Meeting, 2000, IEDM Technical Digest International, 2000, pp. 153-156.			
NMD	CG	Temperature Variation, "The Art of Analog Layout", A. HASTING, Prentice Hall, 1 st Edition, December 2000, P. 164.			
	CH				

Examiner Signature		Date Considered	05/11/2005
-----------------------	--	--------------------	------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

US and Foreign Patent Documents: ¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

Other Prior Art/Non-Patent Literature Documents: ¹Unique citation designation number. ²Applicant is to place a check mark here if English Translation is attached.

Burden Hour Statement: This form is estimated to take 2.0 hours to complete. Time will vary depending upon the needs of the individual case. Any comments on the amount of time you are required to complete this form should be sent to the Chief Information Officer, Patent and Trademark Office, Washington, DC 20231. DO NOT SEND FES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Assistant Commissioner for Patents, Washington, DC 20231